1.8 V USB 3.1 Single Channel Re-driver

Description

The NB7VPQ701M is a 1.8 V single channel re-driver for USB 3.1 Gen 1 and USB 3.1 Gen 2 applications that supports both 5 Gbps and 10 Gbps data rates. Signal integrity degrades from PCB traces, transmission cables, and inter-symbol interference (ISI). The NB7VPQ701M compensates for these losses by engaging varying levels of equalization at the input receiver and de-emphasis on output driver. The output transmitter circuitry provides user selectable de-emphasis and output amplitude settings to create the best eye openings for the outgoing data signals.

The NB7VPQ701M features an intelligent LFPS circuit. This circuit senses the low frequency signals and automatically disables driver de–emphasis for full USB 3.1 Gen 1 and USB 3.1 Gen 2 compliances.

After power up, the NB7VPQ701M periodically checks both of the TX output pairs for a receiver connection. When the receiver is detected the RX termination becomes enabled and the NB7VPQ701M is set to perform the re-driver function.

The NB7VPQ701M comes in a small, ultra-thin 1.6 x 1.6 mm UQFN12 package and is specified to operate across the entire industrial temperature range, -40° C to 85° C.

Features

- 1.8 V \pm 5% Power Supply
- Device Supports USB 3.1 Gen 1 and USB 3.1 Gen 2 Data Rates
- Automatic LFPS De-Emphasis Control
- Automatic Receiver Termination Detection
- Integrated Input and Output Termination
- Selectable Equalization, De-Emphasis, and Output Swing
- Chip Enable Pin for Deep Power–Saving Mode
- Hot-Plug Capable
- ESD Protection ±4 kV HBM
- Operating Temperature Range: -40°C to 85°C
- Small 1.6 x 1.6 x 0.5 mm UQFN12 Package
- This is a Pb–Free Device

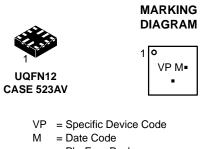
Typical Applications

- Mobile Phone and Tablet
- Computer and Laptop
- Docking Station and Dongle
- Active Cable, Back Planes
- Gaming Console, Smart T.V.



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= Pb–Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

D	evice	Package	Shipping [†]
NB7VPQ	701MMUTBG	UQFN12 (Pb-Free)	3000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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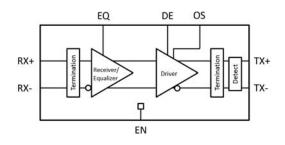
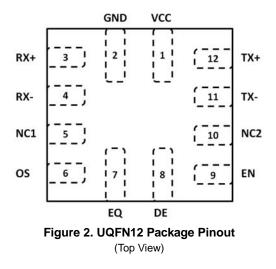


Figure 1. Logic Diagram of NB7VPQ701M



Pin Number	Pin Name	Туре	Description
1	VCC	Power	1.8 V power supply
2	GND	Power	Reference Ground
3	RX+	Differential	Differential input pair for 5 / 10 Gbps USB signals. Must be externally AC-coupled.
4	RX-	Input Pair	
5	NC1	N/A	No connect – float pin
6	OS	CMOS Input	Sets output amplitude on the TX. 3–state input with integrated 250 k Ω pull–up and pull–down resistors. Defaults to Mid when left open.
7	EQ	CMOS Input	Sets equalizer gain on the RX. 3–state input with integrated 250 k Ω pull–up and pull–down resistors. Defaults to Mid when left open.
8	DE	CMOS Input	Sets the output de–emphasis. 3–state input with integrated 250 k Ω pull–up and pull–down resistors. Defaults to Mid when left open.
9	EN	CMOS Input	Chip enable input (active high), internal 550 k Ω pull–up resistor. Low to power down.
10	NC2	N/A	No connect – float pin
11	TX-	Differential	Differential output for 5 / 10 Gbps USB signals. Must be externally AC-coupled.
12	TX+	Output Pair	

Table 1. PIN DESCRIPTION

DEVICE CONFIGURATION

Table 2. CONTROL PIN EFFECTS (Typical Values)

Pin	Description	Logic State		Equalization Gai	n		
EQ	Equalization Amount	Low	3 dB				
		Mid	Mid 6 dB				
		High		9 dB			
			De-ei	mphasis Ratio (N	lote 1)		
Pin	Description	Logic State	OS = LOW	OS = Float	OS = High		
DE	De-Emphasis Amount	Low	0 dB	-4 dB	–6 dB		
		Mid	–3 dB	–5.5 dB	–7.5 dB		
		High	–5.5 dB	–7 dB	–9 dB		
Pin	Description	Logic State		Output Swing	1		
OS	Output Swing with DE Pin Low	Low		750 mV _{PP}			
	(0 dB)	Mid		900 mV _{PP}			
		High		1000 mV _{PP}			
Pin	Description	Logic State	Chip Enable				
EN	Chip Enable Input	Low	Chip Disable	Chip Disabled (Deep Power–Saving Mode)			
		High		Chip Enable			

1. dB Decrease = 20 log * (VTX-DE / VTX-DIFF-PP)

Table 3. ATTRIBUTES

Parameter		
ESD Protection	Human Body Model Charged Device Model	> 4 kV > 1.5 kV
Moisture Sensitivity, Indefinite Time Out of Drypack (Note 2)		Level 1
Flammability Rating	Oxygen Index: 28 to 34	UL 94 V–O @ 0.125 in
Transistor Count		704
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test		

2. For additional information, see Application Note AND8003/D.

Table 4. ABSOLUTE MAXIMUM RATINGS

Over operating free-air temperature range (unless otherwise noted)

Parameter	Description	Min	Мах	Unit
Supply Voltage (Note 3)	V _{CC}	-0.3	2.5	V
Voltage range at any input or	Differential I/O	-0.5	1.89	V
output terminal	LVCMOS inputs	-0.3	V _{CC} + 0.3	V
Electrostatic discharge	Human body model (all pins) (Note 4)		±4	kV
	Charged device model (all pins) (Note 4)		±1.5	kV
Storage temperature, ^T SG		-65	150	°C
Maximum junction temperature, ^T J		-40	125	°C
Junction–to–ambient thermal resistance, θ_{JA}			138	°C/W

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

3. All voltage values are with respect to the GND terminals.

4. Tested in accordance with JEDEC Standard.

Table 5. RECOMMENDED OPERATING CONDITIONS

Over operating free-air temperature range (unless otherwise noted)

Parameter	Description	Min	Nom	Max	Unit
V _{CC}	Main power supply	1.71	1.8	1.89	V
T _A	Operating free-air temperature	-40		+85	°C
C _{AC}	AC coupling capacitor	75	100	200	nF

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

Table 6. POWER SUPPLY CHARACTERISTICS

	Parameter	Test Conditions	Min	Typ (Note 5)	Max	Unit
	Active	Link in U0 with SS data transmission DE = low 0 dB, EQ = low 3 dB, OS = low		65		mA
	Idle State	Link has some activity, not in U0 DE = mid -3 dB, EQ = mid 6dB OS = low		49		mA
I _{CC}	U2/U3	Link in U2 or U3 power saving state DE = mid –3 dB, EQ = mid 6 dB, OS = low		4.5		mA
	No USB Connection	No connection state, termination disabled DE = mid -3 dB, EQ = mid 6 dB, OS = low		4.5		mA
	Deep Power–Saving State	Part disabled by EN pin EN = low		28		μΑ

5. TYP values use $V_{CC} = 1.8 \text{ V}$, $T_A = 25^{\circ}C$.

Table 7. LVCMOS CONTROL PIN CHARACTERISTICS

	Parameter	Test Conditions	Min	Тур	Max	Unit
3-State LVCMOS	Inputs (EQ, DE, OS) and 2-State LVCM	OS Inputs (EN)				
V _{IH}	High-level input voltage		0.8 * V _{CC}		V _{CC}	V
V _{IM}	Mid-level input voltage		0.4 * V _{CC}	V _{CC} / 2	0.6 * V _{CC}	V
VIL	Low-level input voltage		GND		0.2 * ^V CC	V
V _F	Floating voltage	V _{IN} = High impedance		V _{CC} / 2		V
R _{PU}	Internal pull-up resistance			250		kΩ
R _{PD}	Internal pull-down resistance			250		kΩ
Iн	High-level input current	V _{IN} = 1.89 V			20	μΑ
l _{IL}	Low-level input current	$V_{IN} = GND, V_{CC} = 1.89 V$	-20			μΑ

	Parameter	Test Conditions	Min	Тур	Max	Unit
VRX-DIFF-pp	Input differential voltage swing	AC-coupled, peak-to-peak	250		1200	mV _{PP}
VRX-CM	Common-mode voltage bias in the receiver (DC)			V _{CC} - 0.25		V
ZRX-DIFF	Differential input impedance (DC)	Present after an USB device is detected on TX+/TX-	80	100	120	Ω
ZRX-CM	Common-mode input impedance (DC)	Present after an USB device is detected on TX+/TX-	20	25	30	Ω
ZRX-HIGH-IMP	Common-mode input impedance with termination disabled (DC)	Present when no USB device is detected on TX+	25	35		kΩ
VTH-LFPS-pp	Low Frequency Periodic Signaling (LFPS) Detect Threshold	Output voltage is considered squelched below this threshold voltage.			300	mV _{PP}

Table 8. RECEIVER AC/DC CHARACTERISTICS Over operating free-air temperature range (unless otherwise noted)

Table 9. TRANSMITTER AC/DC CHARACTERISTICS Over operating free-air temperature range (unless otherwise noted)

	Parameter	Test Conditions	Min	Тур	Max	Unit
VTX-DIFF-PP	Output differential voltage swing at 5	OS = Low, 50 Ω to V _{CC}		750		mV _{PP}
	Gbps, 10 Gbps with DE low (0 dB)	OS = Mid, 50 Ω to V _{CC}		900		
		OS = High, 50 Ω to V _{CC}		1000		
CTX	TX input capacitance to GND	At 2.5 GHz		1.25		pF
ZTX-DIFF	Differential output impedance (DC)	Present after an USB device is de- tected on TX+/TX-	80	100	120	Ω
ZTX-CM	Common-mode output impedance (DC)	Present after an USB device is de- tected on TX+/TX-	20		30	Ω
ITX-SC	TX short circuit current	TX+ or TX- shorted to GND		30		mA
VTX-CM	Common–mode voltage bias in the transmitter (DC)			V _{CC} -0.5	V _{CC}	V
VTX-CM-ACpp	AC common-mode peak-to-peak volt- age swing in active mode	Within U0 and within LFPS			100	mV _{PP}
VTX-IDLE-DIFF- ACpp	Differential voltage swing during electrical idle	Tested with a high–pass filter	0		10	mV _{PP}
VTX-RXDET	Voltage change to allow receiver detect	Positive voltage to sense receiver termination			600	mV
t _R , t _F	Output rise, fall time	20% – 80% of differential voltage measured 1 inch from the output pin		45		ps
t _{RF-MM}	Output rise, Fall time mismatch	20% – 80% of differential voltage measured 1 inch from the output pin			5	ps
t _{diff-LH} , t _{diff-HL}	Differential propagation delay	De-emphasis = -3 dB, OS = Low propagation delay between 50% level at input and output		150		ps
t _{idleEntry} , ^t idleExit	Idle entry and exit times			30		ns

Table 10. TIMING AND JITTER CHARACTERISTICS

	ms
_	

JITTER FOR 5 Gbps

TJTX-EYE	Total jitter (Notes 6, 7)	EQ = Mid 6 dB, DE = High –5.5 dB, OS = Low	0.087	UI (Note 8)
DJTX	Deterministic jitter (Note 7)		0.023	UI (Note 8)
RJTX	Random jitter (Note 7)		0.006	UI (Note 8)

JITTER FOR 10 Gbps

TJTX-EYE	Total jitter (Notes 6, 7)	EQ = Mid 6dB, DE = High –5.5 dB, OS = Low	0.207	UI (Note 8
DJTX	Deterministic jitter (Note 7)		0.082	UI (Note 8
RJTX	Random jitter (Note 7)		0.013	UI (Note 8

6. Includes RJ at 10⁻¹².

Measured at the ends of reference channel with a K28.5 pattern, VID = 1000 mVpp, -3.5 dB de-emphasis from source.
 5 Gbps, UI = 200 ps for 10 Gbps, UI = 100 ps

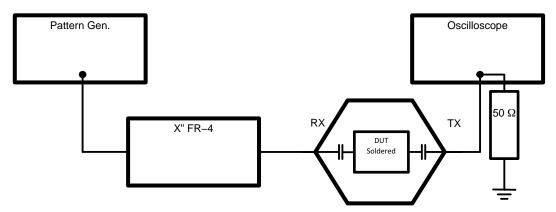


Figure 3. Equalization Measurement Setup

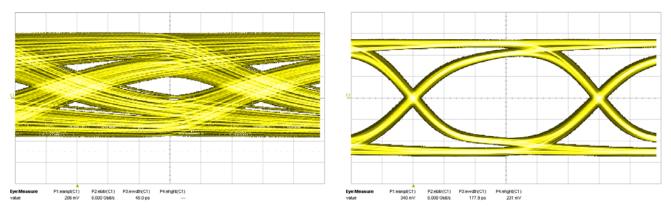


Figure 4. 5 Gbps Signal with 24 inches of FR4 Before Input to NB7VPQ701M and After Using High EQ Setting

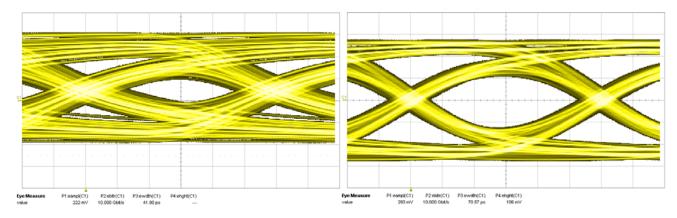


Figure 5. 10 Gbps Signal with 12 inches of FR4 Before Input to NB7VPQ701M and After with EQ Floating (Mid)

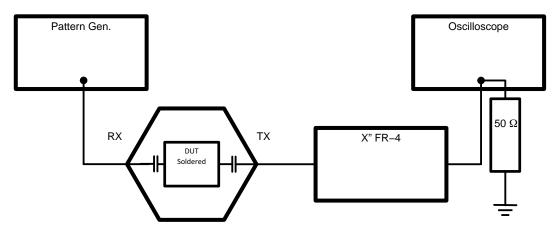


Figure 6. De-Emphasis Measurement Setup

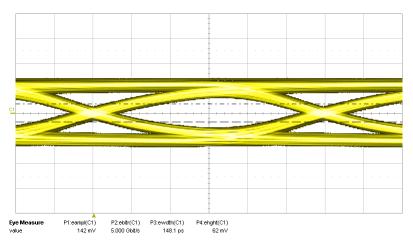


Figure 7. 5 Gbps Signal After 24 inches of FR4 at Output with High DE Setting to NB7VPQ701M

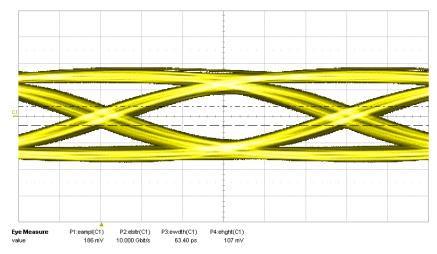


Figure 8. 10 Gbps Signal After 9 inches of FR4 at Output with High DE Setting to NB7VPQ701M

PARAMETER MEASUREMENT DIAGRAMS

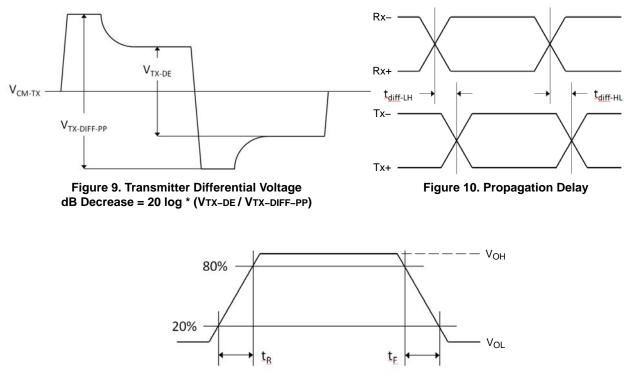


Figure 11. Output Rise and Fall Times

APPLICATION GUIDELINES

LFPS Compliance Testing

As part of USB 3.1 compliance test, the host or peripheral must transmit a LFPS signal that adheres to the spec parameters. When using a real-time oscilloscope to capture this data, *the scope's trigger must be below 0 V when making single-ended measurements*. Although the differential signal is identical to that which is expected by the USB 3.1 system, the AC common mode voltage for LFPS may fall below 0 V during short bursts of switching signal, which is still within the spec's limit.

LFPS Functionality

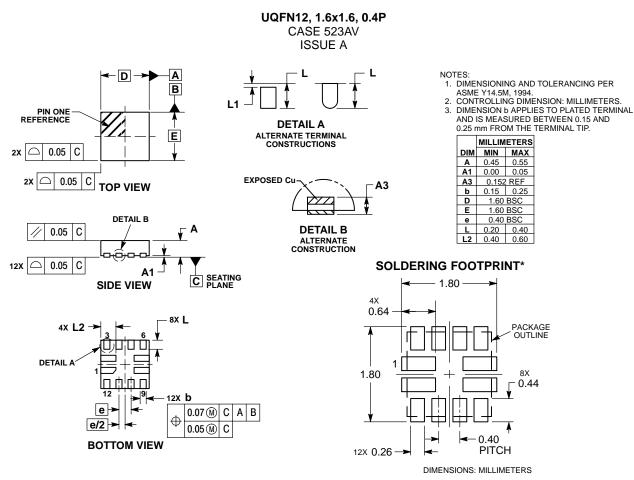
USB 3.1 links use Low Frequency Periodic Signaling (LFPS) to implement functions like exiting low-power modes, performing warm resets and providing link training

between host and peripheral devices. LFPS signaling consists of bursts of frequencies ranging between 10 to 50 MHz and can have specific burst lengths or repeat rates.

Ping.LFPS for TX Compliance

During the transmitter compliance, the system under test must transmit certain compliance patterns as defined by the USB–IF. In order to toggle through these patterns for various tests, the receiver must receive a ping. LFPS signal from either the test suite or a separate pattern generator. The standard signal comprises of a single burst period of 100ns at 20 MHz. In order to pass this signal through NB7VPQ701M, *the duration of the burst must be extended to at least 200 ns.*

PACKAGE DIMENSIONS



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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